

# INTERNATIONAL STANDARD

**IEC**  
**60068-2-69**

Second edition  
2007-05

---

---

## Environmental testing –

### Part 2-69:

### Tests – Test Te: Solderability testing of electronic components for surface mounting devices (SMD) by the wetting balance method



Commission Electrotechnique Internationale  
International Electrotechnical Commission  
Международная Электротехническая Комиссия

PRICE CODE

**T**

*For price, see current catalogue*

## CONTENTS

FOREWORD.....	3
1 Scope.....	5
2 Normative references .....	5
3 Terms and definitions .....	6
4 General description of the method.....	6
5 Description of the test apparatus .....	6
6 Preconditioning .....	7
6.1 Preparation of specimens.....	7
6.2 Ageing.....	7
7 Materials .....	7
7.1 Solder .....	7
7.2 Flux.....	8
8 Procedures.....	8
8.1 Test temperature.....	8
8.2 Solder bath wetting balance procedure.....	8
8.3 Solder globule wetting balance procedure .....	11
9 Presentation of results.....	14
9.1 Form of force versus time trace .....	14
9.2 Test requirements .....	15
10 Information to be given in the relevant specification .....	15
Annex A (normative) Equipment specification .....	16
Annex B (informative) Use of the wetting balance for SMD solderability testing .....	18
Bibliography.....	25
Figure 1 – Test apparatus.....	6
Figure 2 – Typical wetting balance trace .....	14
Table 1 – Recommended solder bath wetting balance test conditions .....	10
Table 2 – Time sequence of the test (solder bath) .....	11
Table 3 – Recommended solder globule wetting balance test conditions.....	12
Table 4 – Time sequence of the test (Solder globule) .....	13

## INTERNATIONAL ELECTROTECHNICAL COMMISSION

## ENVIRONMENTAL TESTING –

**Part 2-69: Tests –  
Test Te: Solderability testing of electronic  
components for surface mounting devices (SMD)  
by the wetting balance method**

## FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC provides no marking procedure to indicate its approval and cannot be rendered responsible for any equipment declared to be in conformity with an IEC Publication.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 60068-2-69 has been prepared by IEC technical committee 91: Electronics assembly technology.

This second edition cancels and replaces the first edition published in 1995 and constitutes a technical revision. The main changes from the previous edition are as follows:

- Inclusion of lead-free alloy test conditions;
- Inclusion of new fluxes for testing, reflecting development of fluxes that have happened in the industry in the past 20 years;
- Inclusion of new component types, and updating test parameters for the whole component list.

The text of this standard is based on the following documents:

FDIS	Report on voting
91/648/FDIS	91/680/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

A list of all the parts in the IEC 60068 series, under the general title *Environmental testing*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

## ENVIRONMENTAL TESTING –

### Part 2-69: Tests – Test Te: Solderability testing of electronic components for surface mounting devices (SMD) by the wetting balance method

#### 1 Scope

This part of IEC 60068 outlines test Te, solder bath wetting balance method and solder globule wetting balance method, applicable for surface mounting devices. These methods determine quantitatively the solderability of terminations on surface mounting devices. IEC 60068-2-54 is also available for surface mounting devices and should be consulted if applicable.

The procedures describe the solder bath wetting balance method and the solder globule wetting balance method and are both applicable to components with metallic terminations and metallized solder pads.

This standard provides the standard procedures for solder alloys containing lead (Pb) and for lead-free solder alloys.

#### 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60068-1, *Environmental testing – Part 1: General and guidance*

IEC 60068-2-20:1979, *Basic environmental testing procedures – Part 2: Tests – Test T: Soldering*  
Amendment 2 (1987)

IEC 60068-2-54:2006, *Environmental testing – Part 2-54: Tests – Test Ta: Solderability testing of electronic components by the wetting balance method*

IEC 61190-1-3:2002, *Attachment materials for electronic assemblies – Part 1-3: Requirements for electronic grade solder alloys and fluxed/non-fluxed solid solder for electronic soldering applications*

ISO 683 (all parts), *Heat-treatable steels, alloy steels and free-cutting steels*

ISO 6362 (all parts), *Wrought aluminium and aluminium alloy extruded rods/bars, tubes and profiles*